ABC development project



infineon



Process description.

_Sawing of substrate and inspection and placement of devices



Features.

_ Magazine load and offloading to Jedec tray Dual pick & place mechanism

_Dual chuck design and dual spindle , one blade / spindle _Vision system with reject units sorting function _Inspection includes (but no limited to): substrate orientation and substrate 2D code reader, device marking quality, broken devices , inked dot , package size X-Y , solder bumps quality ,



SUBSTRATE SIZE : 178 x 127 mm (MAXIMUM)



Final Test



- Fully testing COOLiR²DIE at high current and voltage presents > challenges for a test system and handler
 - Test team chose the LEMSYS test solution
 - Tester capability: 2000A/2000V for static and 2000A/1500V for dynamic testing
- The handler choice was limited due to the package size and > exposed die
- Multitest selected with vertically docked pick & place handlers >
 - A custom manipulator from ESMO was required to provide a working interface on a "headless" LEMSYS tester





Undocked – moves on rails



LEMSYS Test

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Packing



Process description.

_Transfer and inspection of singulated devices from Jedec tray to Tape & Reel packing

Features.



2D inspection system

Loading from Jedec tray or Tape & Reel
Output to Jedec tray or Tape & Reel
Statistics process control tool

____10 head handler for high speed inspection __quadruple pick-and-place head for taping







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